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CCS L55

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21147.3-2016

Methods of measurement for electromagnetic emission of military integrated circuits - Part 3: Radiation emission measurements - Surface scanning

军用集成电路电磁发射测量方法 第3部分：辐射发射测量-表面扫描法

(English Translation)

Issued by: Ministry of Industry and Information Technology

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1 Foreword

SJ 21147.3-2016 is issued by Ministry of Industry and Information Technology.

It is one of 5 parts of the SJ 21147 series.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

2 Scope Preview

SJ 21147.3-2016 is filed under Chinese Standard Classification L55, in the field of electronic components and information technology.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

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3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 16 pages (approximate)

Chinese original: about 24,258 characters

4 Related standards

Other parts of this standard:

SJ 21147.1-2016 - Military integrated circuits - Electromagnetic emission measurement methods - Part 1: General conditions and definitions

SJ 21147.2-2016 - Military integrated circuits - Electromagnetic emission measurement methods - Part 2: Radiation emission measurements - TEM cells and broadband TEM chamber

SJ 21147.4-2016 - Part 4: Conducted emission measurements - 1omega /150omega direct coupling method

SJ 21147.5-2016 - Part 5: Conducted emission measurements - Workbench Faraday cage method

Standards on related subjects:

GB/T 46280.2-2025 - Specification for chiplet interconnection interface - Part 2: Protocol layer technical requirements

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

5 Classification and status

Chinese Standard Classification (CCS): L 55

Prefix SJ: mandatory standard.

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